

# The Rigaku Journal

An International Journal of X-ray Characterization

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*The Rigaku Journal* is semiannually published by Rigaku Corporation to serve the X-ray analysis community in general, and Rigaku instrumentation users in particular. *The Rigaku Journal* contains various scientific and technical information, carrying articles related to a wide range of X-ray diffraction and fluorescence applications.

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## EDITORIAL

# New Journal Policy and Editorial Staff

Two important goals for the Rigaku Journal are:

1. To publish high-quality technical articles and reports that will provide useful information for the readers of the Rigaku Journal.
2. To establish and improve communication between Rigaku and its current and future users.

In order to achieve these goals, articles published in the Rigaku Journal will be composed of: technical articles, review articles, application reports and product reports. Technical articles and review articles are invited papers mostly from authors outside of Rigaku. Application reports and product reports are contributed papers mainly by scientists and engineers from Rigaku companies in Japan and around the world.

To improve the quality and services, the Journal's editorial staff is expanded and reorganized to include: Editor-in-Chief, Associate Editor-in-Chief, Co-editors, Assistant Editors, and Managing Editor. A complete list of the editorial staff is listed in the masthead. The Editor-in-Chief, Associate Editor-in-Chief and Co-editors are responsible for identifying and inviting technical and review articles for the Journal. To thank the contributions by our invited authors, an honorarium will be presented to each invited article published in the Journal. An appreciation certificate will also be presented to each author of an invited article. Assistant Editors have the responsibility of soliciting application and product reports for the Journal. These reports are contributed mostly by authors from Rigaku companies in Japan and around the world. An appreciation certificate will be presented to each author of a published report. The Managing Editor will handle non-technical matters for the Journal.

We are delighted to report that a new Editorial Advisory Board has also been formed recently. As shown in the masthead, four members on the Board are executives of Rigaku companies and two are from organizations outside of Rigaku. We appreciate all six members very much for accepting our invitations to serve on the Editorial Advisory Board. Their valuable advices and suggestions certainly will help the Journal to better serve the X-ray analysis community in general and Rigaku product users in particular.

The Rigaku Journal is distributed to our readers free of charge. At the time where international renowned companies such as Philips and Siemens withdrew from X-ray equipment manufacturing business, Rigaku remains confident and committed deeper in X-rays. To publish the Rigaku Journal is just one of Rigaku's commitments and contributions to the X-ray and crystallography communities. We believe that our new policy will help us to publish a high-quality journal. Please let us know if you have any suggestions.

Last, but not least, we would like to congratulate Dr. Tomoya Arai, of the Rigaku Industrial Corporation, Osaka, Japan, for receiving the prestigious 2004 Birks Award. The Birks Award was established in 1986 by the Denver X-ray Conference Organizing Committee to recognize outstanding contributions to the X-ray spectroscopy field. The Award was named in honor of L.S. (Verne) Birks for his many contributions to X-ray analysis. The Award is presented biennially at the Denver X-ray Conference. The 2004 Birks Award recognized Dr. Arai's dedication, efforts, and contributions in the design of equipments, and his research that resulted in the advancement of the use of X-rays for the study of thin films, semiconductors, and other materials using the X-ray fluorescence technique. To celebrate the Award and at the request of the Rigaku Journal, Dr. Arai has prepared an invited article entitled "Analytical Precision and Accuracies in X-ray Fluorescence Analysis" for publication in this November issue of the Rigaku Journal. Enjoy!

Hideo Toraya  
Editor-in-Chief

Ting C. Huang  
Associate Editor-in-Chief